

MSE-351

**Surface analysis**

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Cursus	Sem.	Type
Materials Science and Engineering	MA1, MA3	Opt.

Language of teaching	English
Credits	3
Withdrawal	Unauthorized
Session	Winter
Semester	Fall
Exam	Written
Workload	90h
Weeks	14
<b>Hours</b>	<b>3 weekly</b>
Courses	2 weekly
TP	1 weekly
<b>Number of positions</b>	<b>18</b>

**It is not allowed to withdraw from this subject after the registration deadline.**

**Summary**

The course treats the main surface analysis methods for the characterization of surfaces, interfaces and thin films. It discusses how these methods can be applied to gain specific knowledge about structural, chemical and functional properties of surfaces and thin films. Limitation to 18 students!

**Content**

1. Introduction
2. Introduction to electronic states on atoms
3. Photo Electron Spectroscopy and Chemical Analysis (ESCA/XPS)
4. Auger Electron Spectroscopy (AES)
5. Secondary Ion Mass Spectrometry (SIMS)
6. Depth profiling
7. Electron diffraction from surfaces
8. Scanning Tunnelling Microscopy (STM)
9. Atomic Force Microscopy (AFM)
10. Quantitative measurements of surface properties with AFM

**Keywords**

electronic states on atoms, angular momentum, spin, particle wavelength, photoélectrons, energy analyzers, chemical composition, interatomic forces like van der Waal's, surface topography, image of magnetic and piezoelectric responses

**Learning Outcomes**

By the end of the course, the student must be able to:

- Describe the main features of surface analysis
- Differentiate advantages and disadvantages
- Choose the appropriate methodes

**Transversal skills**

- Use a work methodology appropriate to the task.
- Access and evaluate appropriate sources of information.
- Evaluate one's own performance in the team, receive and respond appropriately to feedback.

**Teaching methods**

ex-cathedra and exercises / TP: experimental work with assistants on XPS or AFM in groups of about 4 / presentation on results and interpretation

**Expected student activities**

learn, look up, make exercises

**Assessment methods**

written exam

**Resources****Bibliography**

Leonard C. Feldmann and James W. Mayer, Fundamentals of surface and thin film analysis , North-Holland, (Elsevier) 1986

Hans Jörg Mathieu, Erich Bergmann, and René Gras, Analyse et technologie des surfaces , Presses polytechniques et universitaires romandes, 2003.

D.J. O' Connor, B.A. Sexton, R.St.C. Smart (eds), Surface analysis methods in materials science , Springer, 2003.

**Ressources en bibliothèque**

- [Analyse et technologies des surfaces / Mathieu](#)
- [Fundamentals of surface and thin film analysis / Feldman](#)
- [Surface analysis methods in materials science / Connor](#)

**Notes/Handbook**

copies of foils, script available as pdf file

**Moodle Link**

- <http://moodle.epfl.ch>